TOSHIBA Transistor Silicon NPN Epitaxial Type

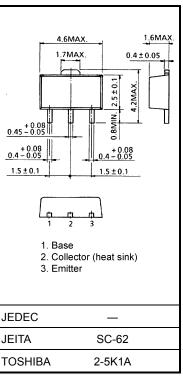
# 2SC5810

High-Speed Switching Applications DC-DC Converter Applications Strobe Applications

- High DC current gain:  $h_{FE} = 400$  to 1000 (IC = 0.1 A)
- Low collector-emitter saturation voltage:  $V_{CE}$  (sat) = 0.17 V (max)
- High-speed switching: tf = 85 ns (typ.)

#### Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V <sub>CBO</sub>	100	V	
Collector-emitter voltage		V <sub>CEX</sub>	80	V	
		V <sub>CEO</sub>	50		
Emitter-base voltage		V <sub>EBO</sub>	7	V	
Collector current	DC	Ι <sub>C</sub>	1.0	A	
	Pulse	I <sub>CP</sub>	2.0		
Base current		Ι <sub>Β</sub>	0.1	А	
Collector power dissipation	DC	P <sub>C</sub> (Note)	2.0	W	
	t = 10 s	FC (NOIG)	1.0		
Junction temperature		Тј	150	°C	
Storage temperature range		T <sub>stg</sub>	-55 to 150	°C	



Weight: 0.05 g (typ.)

### Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I <sub>CBO</sub>	V <sub>CB</sub> = 100 V, I <sub>E</sub> = 0	_	_	100	nA
Emitter cut-off current		I <sub>EBO</sub>	V <sub>EB</sub> = 7 V, I <sub>C</sub> = 0	_	_	100	nA
Collector-emitter breakdown voltage		V (BR) CEO	I <sub>C</sub> = 10 mA, I <sub>B</sub> = 0	50	_	_	V
DC current gain		h <sub>FE</sub> (1)	V <sub>CE</sub> = 2 V, I <sub>C</sub> = 0.1 A	400	-	1000	
		h <sub>FE</sub> (2)	V <sub>CE</sub> = 2 V, I <sub>C</sub> = 0.3 A	200	_	_	
Collector-emitter saturation voltage		V <sub>CE (sat)</sub>	I <sub>C</sub> = 300 mA, I <sub>B</sub> = 6 mA	_	_	0.17	V
Base-emitter saturation voltage		V <sub>BE (sat)</sub>	I <sub>C</sub> = 300 mA, I <sub>B</sub> = 6 mA	_	-	1.10	V
Collector output capacitance		C <sub>ob</sub>	V <sub>CB</sub> = 10 V, I <sub>E</sub> = 0, f = 1 MHz	_	5	_	pF
Switching time	Rise time	tr	See Figure 1.	_	35		ns
	Storage time	t <sub>stg</sub>	V <sub>CC</sub> ≈ 30 V, R <sub>L</sub> = 100 Ω	_	680	—	
	Fall time	t <sub>f</sub>	I <sub>B1</sub> = −I <sub>B2</sub> = 10 mA	_	85	_	

Unit: mm

Note: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area:  $645 \text{ mm}^2$ )

## Marking

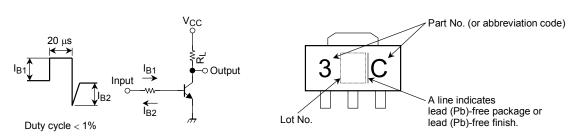
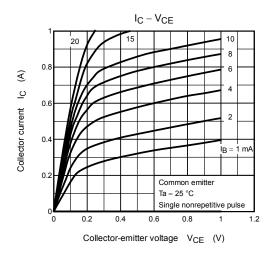
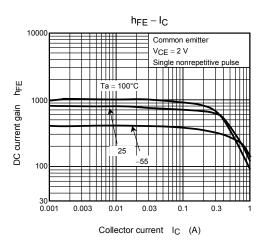
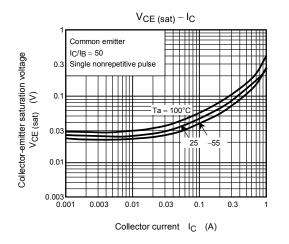


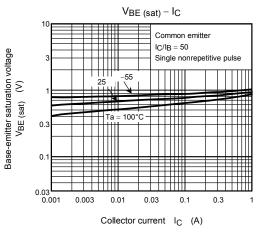
Figure 1 Switching Time Test Circuit & Timing Chart

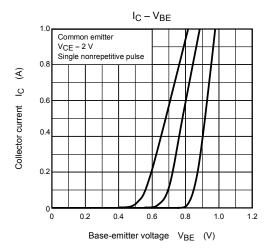
# **TOSHIBA**

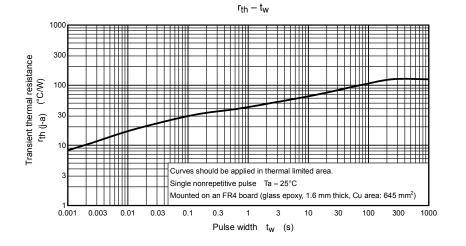


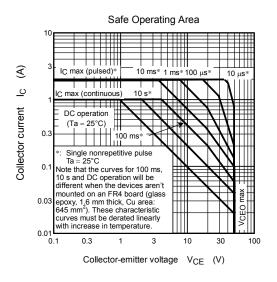












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